ICI E450 L-EFT

Pulse E-Field Source

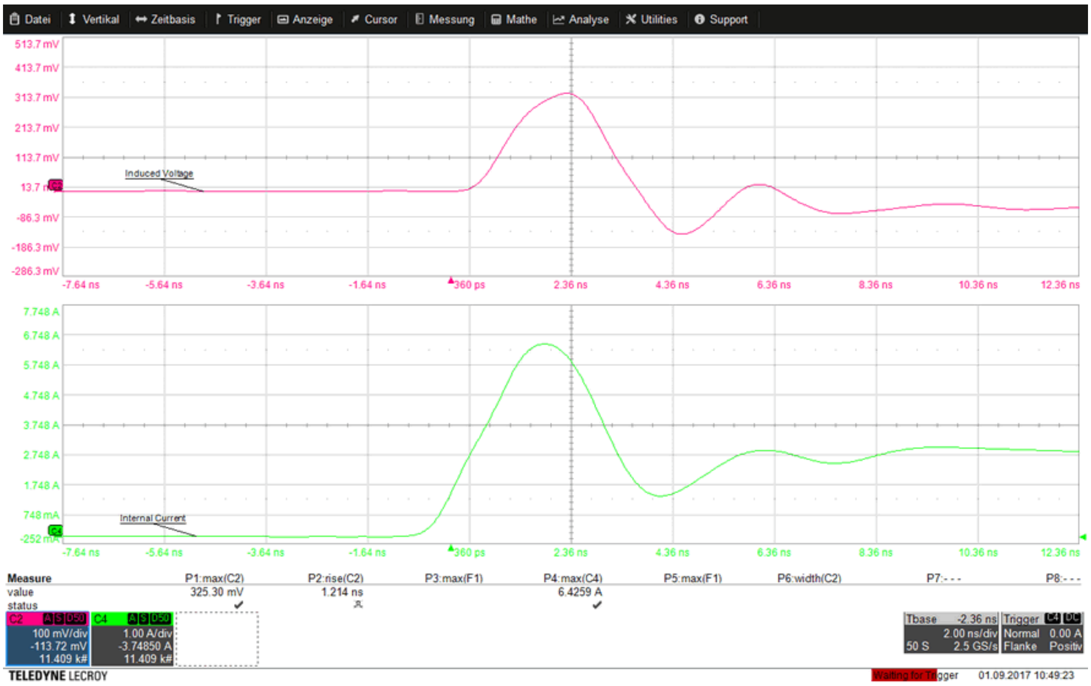
Short description

The ICI E450 L-EFT pulse electric field source couples fast transient pulses into a test IC (open die). This allows for fault injection attacks or testing the immunity of individual areas of the IC.

Technical parameters

Probe head dimensions:	Ø 450 µm
Max. Displacement Current (Stripline 100 µm)	7 mA
Pulse parameter	
Rise time	< 2 ns
Repetition frequency	0.1 Hz - 20 kHz
Polarity (set by software)	+ / - / alternating
Measuring output	50 Ω
Trigger-pulse delay (Bypass Mode - Delay Line)	
min. Trigger-pulse delay (typ.)	70 ns
max. Trigger-pulse delay (typ.)	420 ns
max. Jitter (typ.)	± 1 ns
Supply voltage	BPS 202
Weight	70 g
Sizes (L x W x H)	(26 x 43 x 53) mm

Pulse shape



Measure	P1:max(C2)	P2:rise(C2)	P3:max(F1)	P4:max(C4)	P5:max(F1)	P6:width(C2)	P7:- - -	P8:- - -
value	325.30 mV	1.214 ns		6.4259 A				
status	✓			✓				

C2 A S D50
100 mV/div
-113.72 mV
11.409 k#

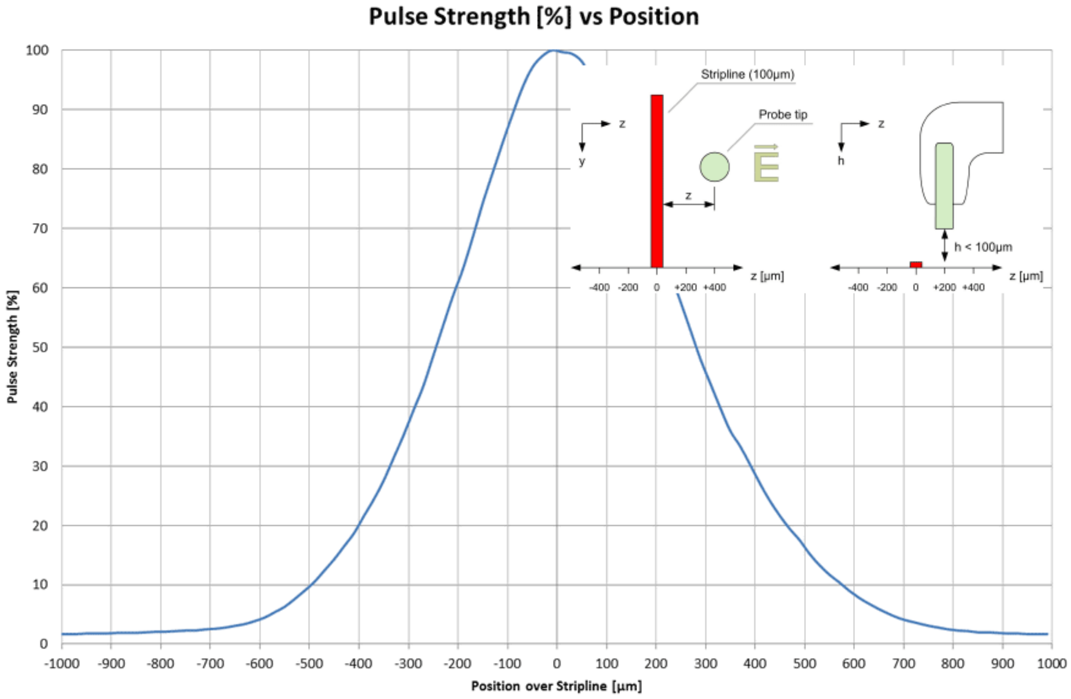
C4 A S D50
1.00 A/div
-3.74850 A
11.409 k#

Tbase -2.36 ns
50 S 2.00 ns/div 2.5 GS/s

Trigger C4 DC
Normal 0.00 A
Flanke Positiv

Waiting for Trigger 01.09.2017 10:49:23

Transverse scan



Application of ICI E450 L-EFT pulse E-field source